

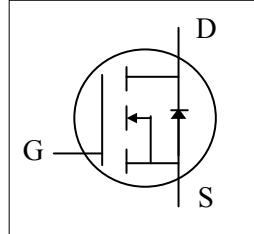
XP4NA1R4CMT-A

Halogen-Free Product

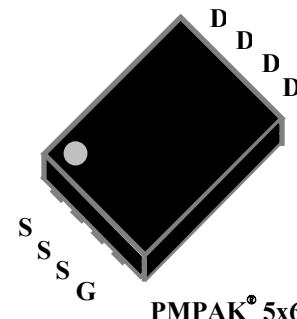


**N-CHANNEL ENHANCEMENT MODE
POWER MOSFET**

- ▼ 100% R_g & UIS Test
- ▼ Simple Drive Requirement
- ▼ Ultra Low On-resistance
- ▼ RoHS Compliant & Halogen-Free



BV_{DSS}	45V
$R_{DS(ON)}$	1.4mΩ



PMPAK® 5x6

Description

XP4NA1R4C series are innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The PMPAK® 5x6 package is special for DC-DC converters application and the foot print is compatible with SO-8 with backside heat sink and lower profile.

Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	45	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^4$ (Silicon Limited)	223	A
$I_D @ T_C = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^4$	100	A
$I_D @ T_A = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^3$	49	A
$I_D @ T_A = 70^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^3$	39	A
I_{DM}	Pulsed Drain Current ¹	400	A
$P_D @ T_C = 25^\circ\text{C}$	Total Power Dissipation	104	W
$P_D @ T_A = 25^\circ\text{C}$	Total Power Dissipation ³	5	W
E_{AS}	Single Pulse Avalanche Energy ⁵	125	mJ
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
R_{thj-c}	Maximum Thermal Resistance, Junction-case	1.2	°C/W
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient ³	25	°C/W

Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=250\mu\text{A}$	45	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_{\text{D}}=20\text{A}$	-	-	1.4	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_{\text{D}}=20\text{A}$	-	-	2.5	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{D}}=250\mu\text{A}$	1	-	3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}$, $I_{\text{D}}=20\text{A}$	-	110	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=36\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	10	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	100	nA
Q_{g}	Total Gate Charge	$I_{\text{D}}=20\text{A}$	-	47	75.2	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=20\text{V}$	-	12	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=4.5\text{V}$	-	23	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DS}}=20\text{V}$	-	14	-	ns
t_{r}	Rise Time	$I_{\text{D}}=20\text{A}$	-	42	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_{\text{G}}=1\Omega$	-	42	-	ns
t_{f}	Fall Time	$V_{\text{GS}}=10\text{V}$	-	11	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	4500	7200	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=20\text{V}$	-	1800	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	150	-	pF
R_{g}	Gate Resistance	f=1.0MHz	-	1	2	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_{\text{S}}=20\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	1.3	V
t_{rr}	Reverse Recovery Time	$I_{\text{S}}=20\text{A}$, $V_{\text{GS}}=0\text{V}$, $dI/dt=100\text{A}/\mu\text{s}$	-	48	-	ns
Q_{rr}	Reverse Recovery Charge		-	45	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² copper pad of FR4 board, t \leq 10sec ; 60°C/W at steady state.
- 4.Package limitation current is 100A .
- 5.Starting $T_j=25^\circ\text{C}$, $V_{\text{DD}}=30\text{V}$, $L=0.1\text{mH}$, $R_{\text{G}}=25\Omega$

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT, AUTOMOTIVE OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

XSEMI DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

XSEMI RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN.

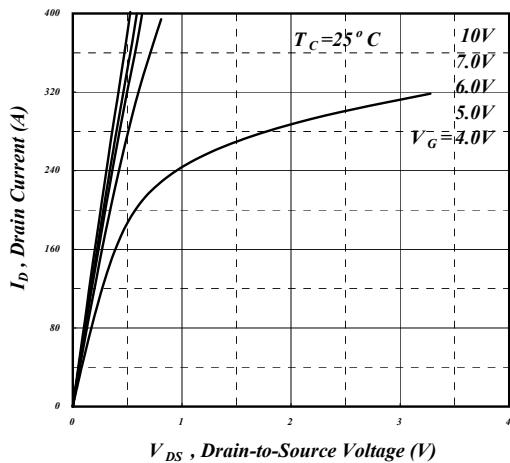


Fig 1. Typical Output Characteristics

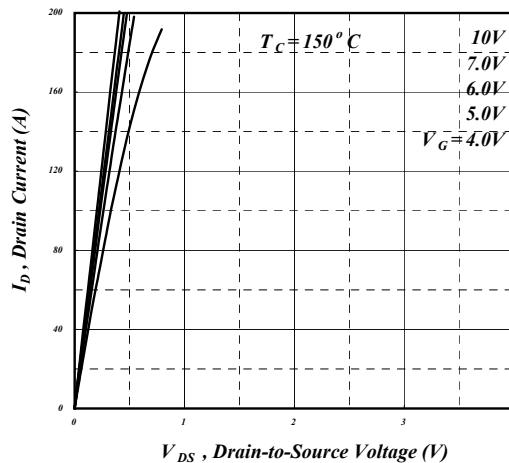


Fig 2. Typical Output Characteristics

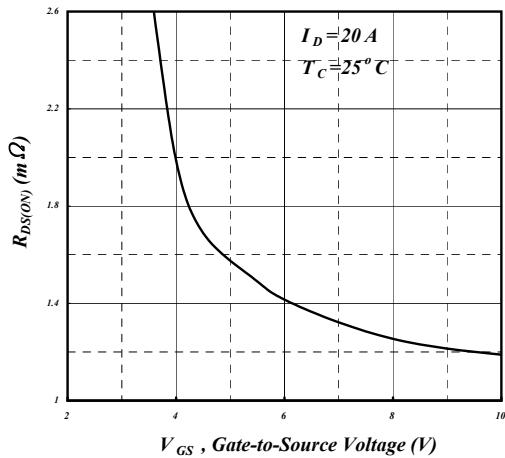


Fig 3. On-Resistance v.s. Gate Voltage

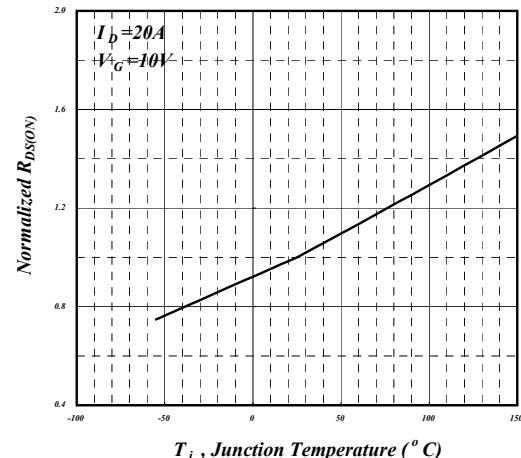


Fig 4. Normalized On-Resistance v.s. Junction Temperature

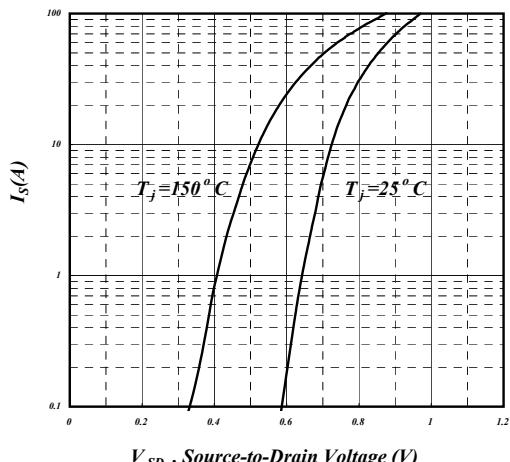


Fig 5. Forward Characteristic of Reverse Diode

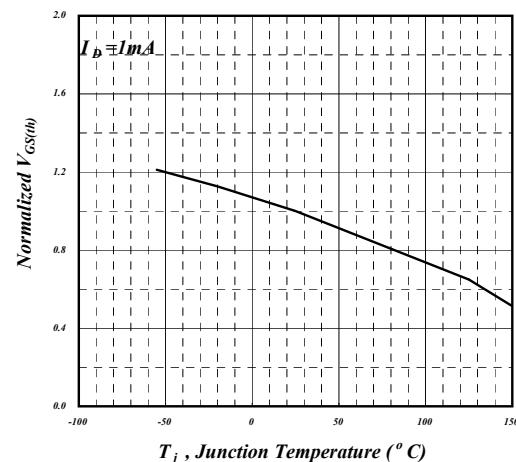
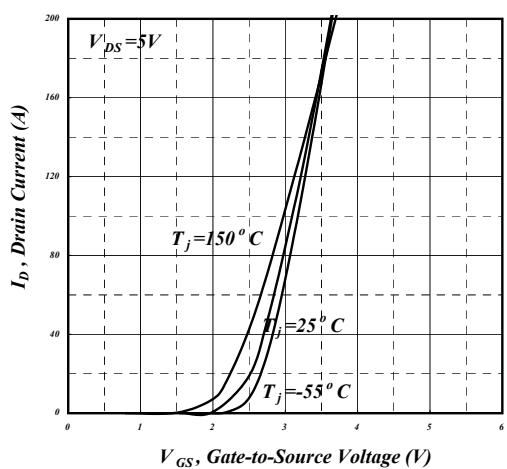
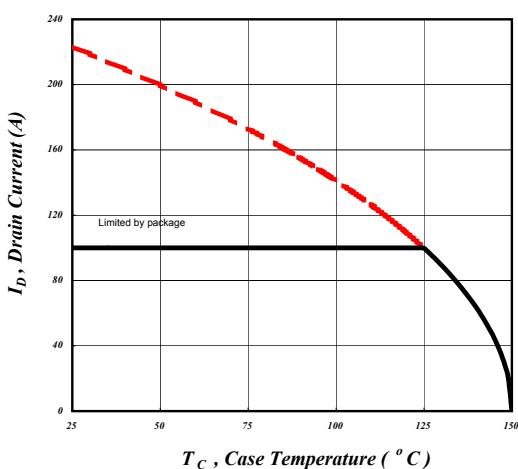
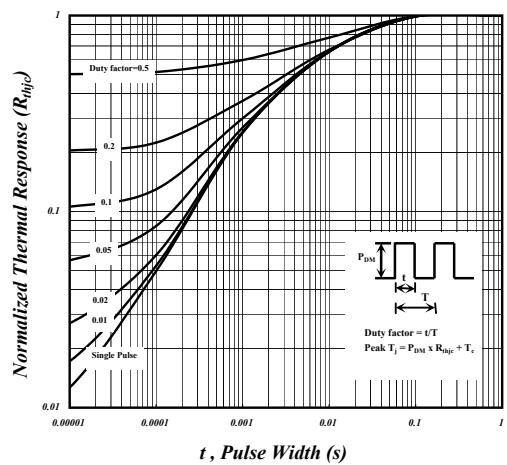
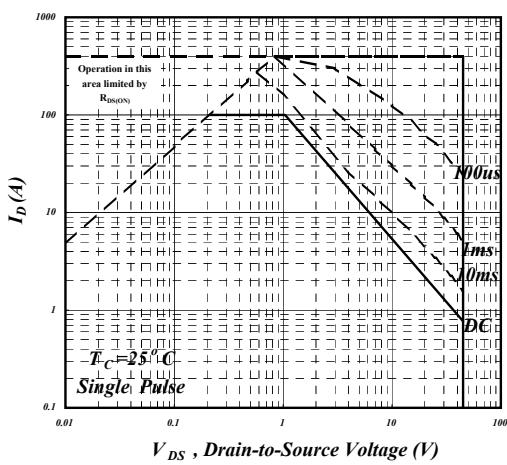
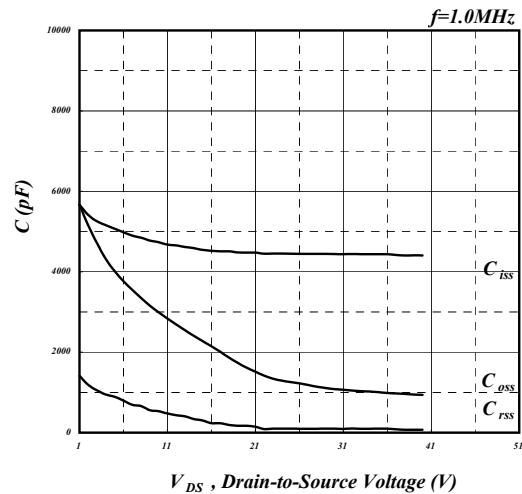
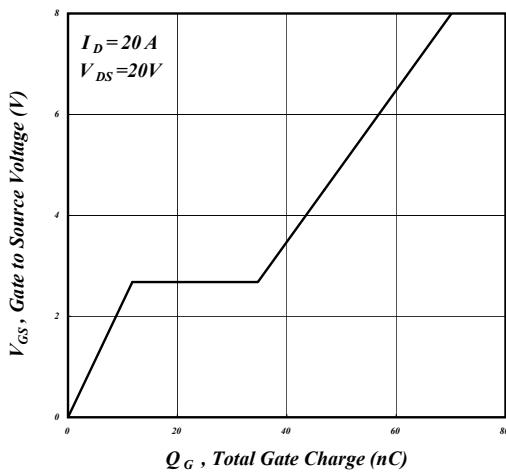


Fig 6. Gate Threshold Voltage v.s. Junction Temperature



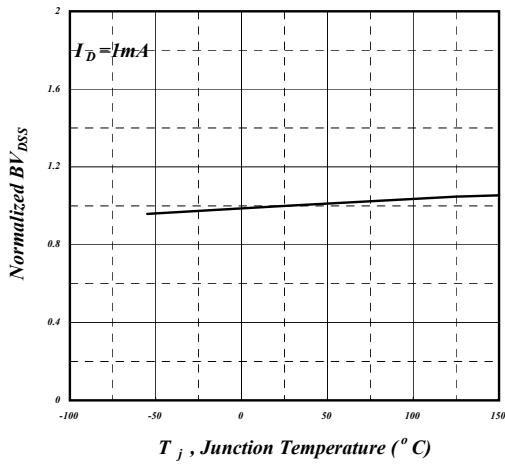


Fig 13. Normalized BV_{DSS} v.s. Junction Temperature

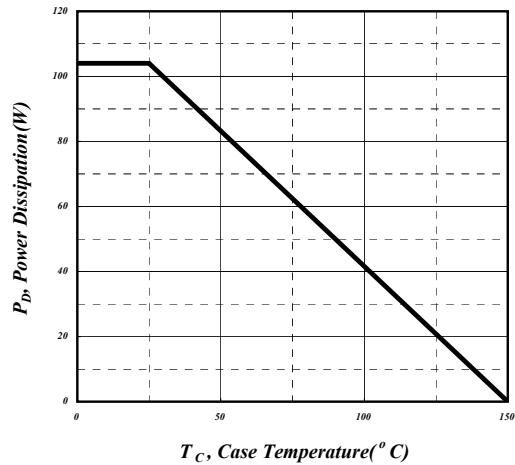


Fig 14. Total Power Dissipation

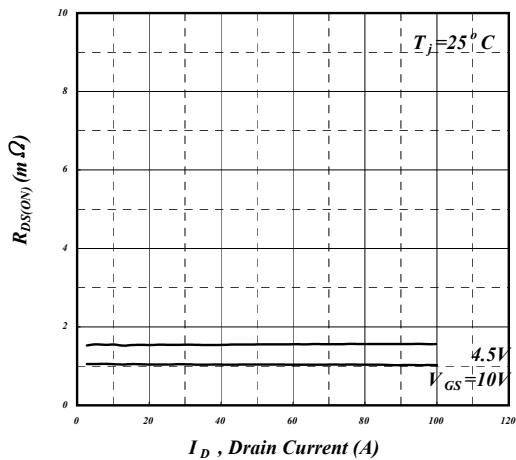


Fig 15. Typ. Drain-Source on State Resistance